

Notice of References Cited	Application/Control No. 09/847,590		Applicant(s)/Patent Under Reexamination BURKHART, REED	
	Examiner SARGON N. NANO		Art Unit 2457	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,598,027	07-2003	Breen et al.	705/26
*	B	US-7,054,938	05-2006	Sundqvist et al.	709/227
*	C	US-7,007,076	02-2006	Hess et al.	709/219
*	D	US-7,421,468	09-2008	Lunenfeld, Harvey	709/203
*	E	US-6,058,417	05-2000	Hess et al.	709/219
*	F	US-6,415,320	07-2002	Hess et al.	709/219
*	G	US-5,794,219	08-1998	Brown, Stephen J.	705/37
*	H	US-6,023,686	02-2000	Brown, Stephen J.	705/37
*	I	US-6,167,386	12-2000	Brown, Stephen J.	705/37
*	J	US-6,415,269	07-2002	Dinwoodie, David Lionel	705/36R
*	K	US-6,671,674	12-2003	Anderson et al.	705/26
*	L	US-6,677,858	01-2004	Faris et al.	340/573.1
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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